



ALPHA & OMEGA
SEMICONDUCTOR

AOT402

N-Channel Enhancement Mode Field Effect Transistor

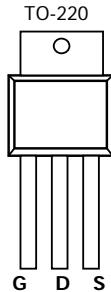


General Description

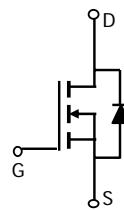
The AOT402 uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. This device is suitable for use in PWM, load switching and general purpose applications. Standard Product AOT402 is Pb-free (meets ROHS & Sony 259 specifications). AOT402L is a Green Product ordering option. AOT402 and AOT402L are electrically identical.

Features

$V_{DS} (V) = 105V$
 $I_D = 110 A \quad (V_{GS} = 10V)$
 $R_{DS(ON)} < 8.6 \text{ m}\Omega \quad (V_{GS} = 10V) @ I_D = 30A$
 $R_{DS(ON)} < 10 \text{ m}\Omega \quad (V_{GS} = 6V)$



Top View
Drain Connected
to Tab



Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DS}	105	V
Gate-Source Voltage	V_{GS}	± 25	V
Continuous Drain Current ^G	I_D	110	A
$T_C=100^\circ\text{C}$		85	
Pulsed Drain Current ^C	I_{DM}	200	
Avalanche Current ^C	I_{AR}	100	A
Repetitive avalanche energy $L=0.3\text{mH}$ ^C	E_{AR}	540	mJ
Power Dissipation ^B	P_D	300	W
$T_C=100^\circ\text{C}$		150	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 175	°C

Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A	Steady-State	$R_{\theta JA}$	47	°C/W
Maximum Junction-to-Case ^B	Steady-State	$R_{\theta JC}$	0.25	°C/W

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units	
STATIC PARAMETERS							
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=10\text{mA}, V_{GS}=0\text{V}$	105			V	
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=84\text{V}, V_{GS}=0\text{V}$	$T_J=55^\circ\text{C}$	1	5	μA	
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 25\text{V}$			100	nA	
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	2	3.3	4	V	
$I_{\text{D(ON)}}$	On state drain current	$V_{GS}=10\text{V}, V_{DS}=5\text{V}$	200			A	
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=30\text{A}$		6.9	8.6	$\text{m}\Omega$	
			$T_J=125^\circ\text{C}$		12.8		
		$V_{GS}=6\text{V}, I_D=30\text{A}$			7.9	10	$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{DS}=5\text{V}, I_D=30\text{A}$			88	S	
V_{SD}	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$			0.7	1	V
I_s	Maximum Body-Diode Continuous Current				110	A	
DYNAMIC PARAMETERS							
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=25\text{V}, f=1\text{MHz}$		7.7	10	nF	
C_{oss}	Output Capacitance			820		pF	
C_{rss}	Reverse Transfer Capacitance			300		pF	
R_g	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		1.25	2	Ω	
SWITCHING PARAMETERS							
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=25\text{V}, I_D=30\text{A}$		182	230	nC	
Q_{gs}	Gate Source Charge			54		nC	
Q_{gd}	Gate Drain Charge			44		nC	
$t_{\text{D(on)}}$	Turn-On DelayTime	$V_{GS}=10\text{V}, V_{DS}=25\text{V}, R_L=0.75\Omega, R_{\text{GEN}}=3\Omega$		30.5		ns	
t_r	Turn-On Rise Time			42.5		ns	
$t_{\text{D(off)}}$	Turn-Off DelayTime			66		ns	
t_f	Turn-Off Fall Time			16		ns	
t_{rr}	Body Diode Reverse Recovery Time	$I_F=30\text{A}, dI/dt=100\text{A}/\mu\text{s}$		86	115	ns	
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=30\text{A}, dI/dt=100\text{A}/\mu\text{s}$		375		nC	

A: The value of R_{QJA} is measured with the device in a still air environment with $T_A=25^\circ\text{C}$.B. The power dissipation P_D is based on $T_{J(\text{MAX})}=175^\circ\text{C}$, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.C: Repetitive rating, pulse width limited by junction temperature $T_{J(\text{MAX})}=175^\circ\text{C}$.D. The R_{QJA} is the sum of the thermal impedance from junction to case R_{QJC} and case to ambient.E. The static characteristics in Figures 1 to 6 are obtained using $<300\ \mu\text{s}$ pulses, duty cycle 0.5% max.F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{J(\text{MAX})}=175^\circ\text{C}$.

G. The maximum current rating is limited by bond-wires.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

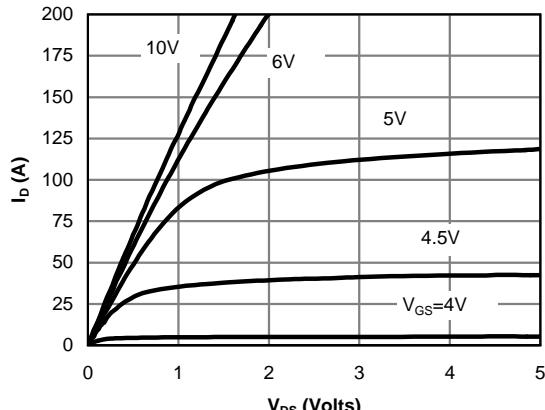


Fig 1: On-Region Characteristics

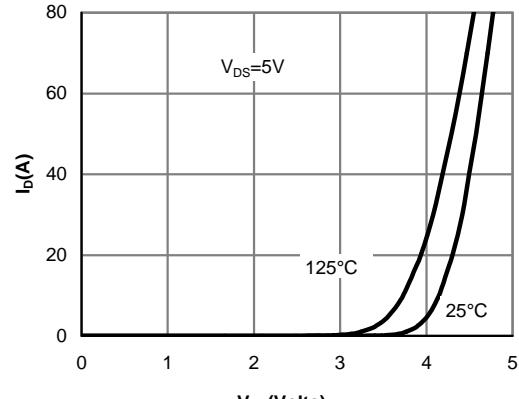


Figure 2: Transfer Characteristics

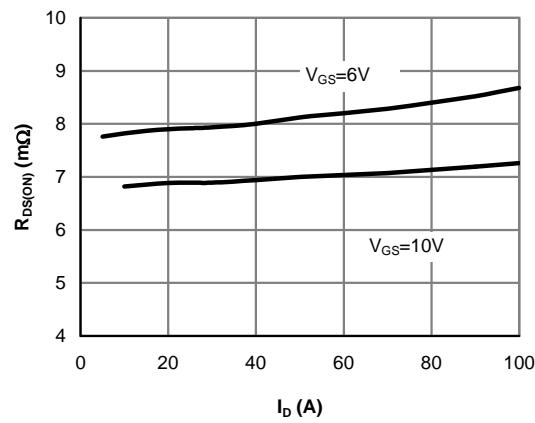


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

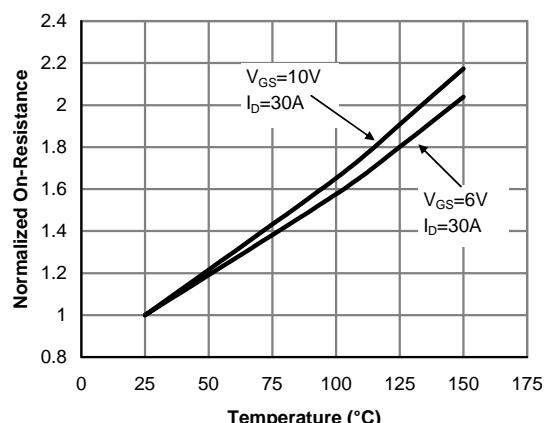


Figure 4: On-Resistance vs. Junction Temperature

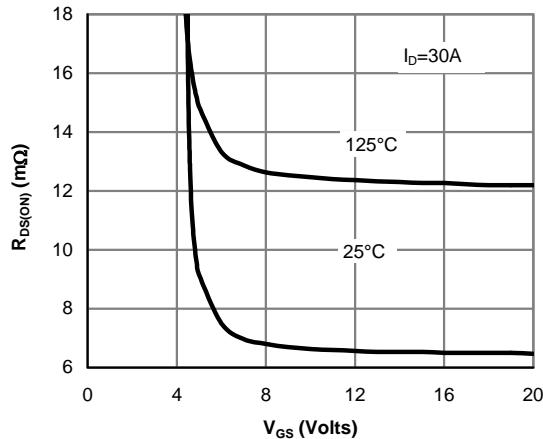


Figure 5: On-Resistance vs. Gate-Source Voltage

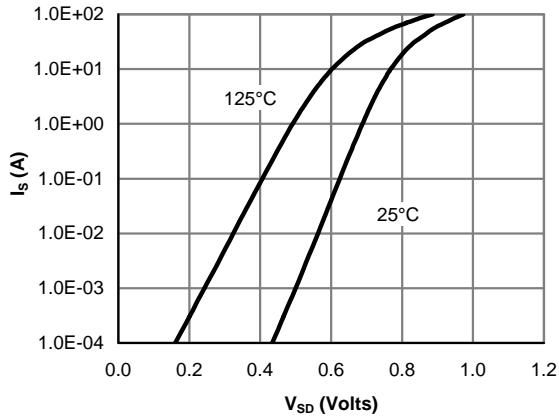


Figure 6: Body-Diode Characteristics

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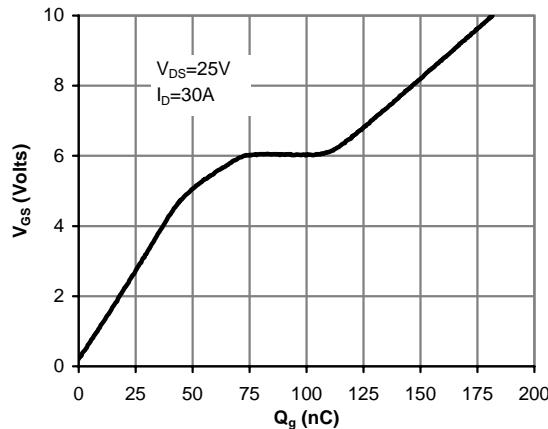


Figure 7: Gate-Charge Characteristics

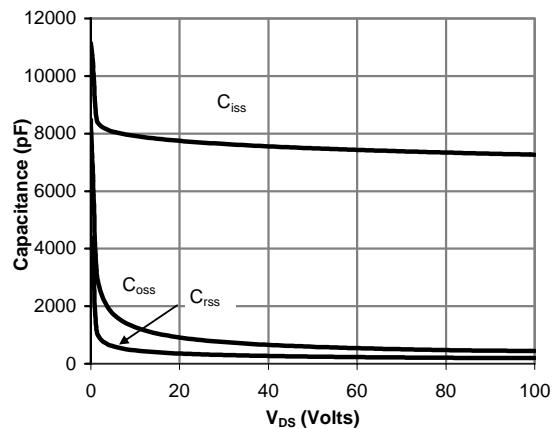


Figure 8: Capacitance Characteristics

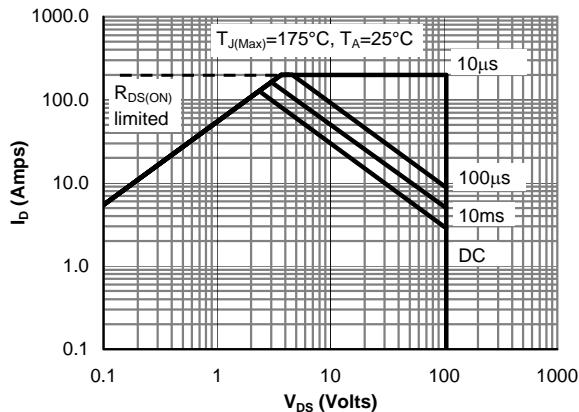


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

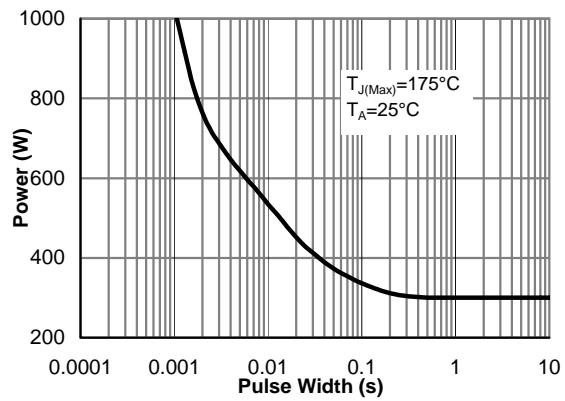


Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)

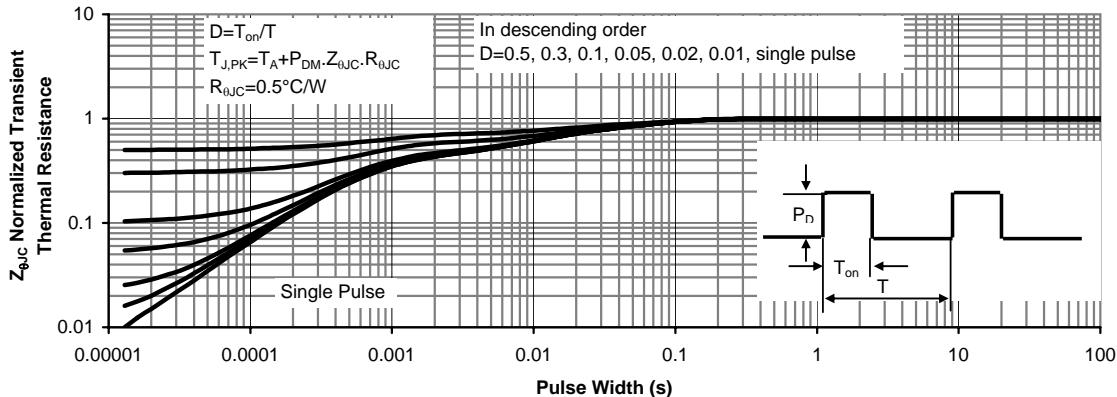


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

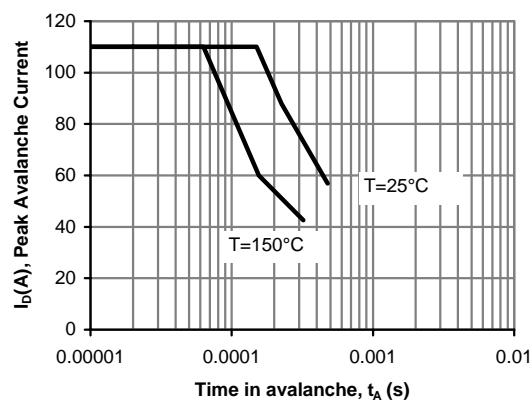
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 12: Single Pulse Avalanche capability

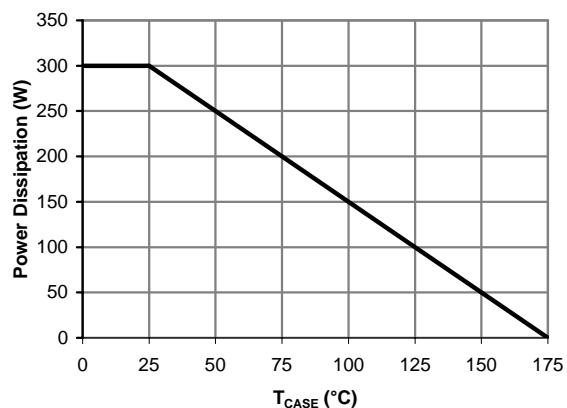


Figure 13: Power De-rating (Note B)

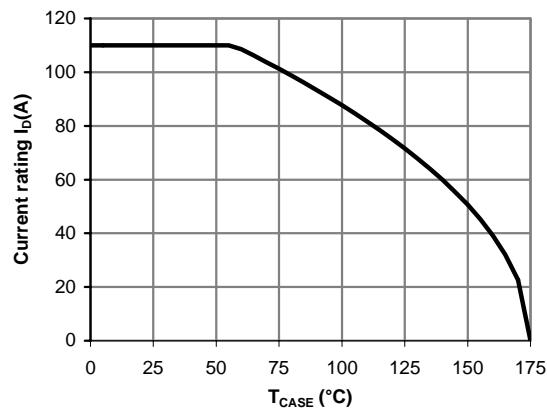


Figure 14: Current De-rating (Note B)